

Title (en)
VARIABLE RESISTOR ARRANGEMENT, MEASUREMENT BRIDGE CIRCUIT AND METHOD FOR CALIBRATING A MEASUREMENT BRIDGE CIRCUIT

Title (de)
VARIABLE WIDERSTANDSANORDNUNG, MESSBRÜCKENSCHALTUNG UND VERFAHREN ZUM KALIBRIEREN EINER MESSBRÜCKENSCHALTUNG

Title (fr)
SYSTÈME VARIABLE DE RÉSISTANCE, CIRCUIT EN PONT DE MESURE ET PROCÉDÉ D'ÉTALONNAGE D'UN CIRCUIT EN PONT

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Application
EP 12769964 A 20120906

Priority
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• EP 2012067374 W 20120906

Abstract (en)
[origin: WO2013064294A1] The invention relates to a measurement bridge circuit (100), having a first and a second branch. The first branch contains a first resistor (R2(x)) which is sensitive to measured variables and an invariable resistor (Rfix,1) connected in series, with a first tap point (104) being arranged between the first resistor (R2(x)) which is sensitive to measured variables and the invariable resistor (Rfix,1). The second branch contains a second resistor (R1(x)) which is sensitive to measured variables and a variable resistor arrangement (102) connected in series. The variable resistor arrangement (102) has a first component (Rfix,2) having an invariable electrical resistance value and a second component (M) having a variable electrical resistance value, the second component being connected in parallel with the first component (Rfix,2) in order to vary a total electrical resistance value for the resistor arrangement (102). A second tap point (106) is arranged between the second resistor (R1(x)) which is sensitive to measured variables and the resistor arrangement (102). The first branch and the second branch are connected in parallel. A measuring instrument can be arranged between the first tap point (104) and the second tap point (106).

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Citation (search report)
See references of WO 2013064294A1

Citation (examination)
• US 7106120 B1 20060912 - HSU SHENG TENG [US]
• US 3893192 A 19750701 - JENSEN ARNE
• WO 2011099961 A1 20110818 - HEWLETT PACKARD DEVELOPMENT CO [US], et al

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